

# C2M0045170D

Silicon Carbide Power MOSFET  
C2M™ MOSFET Technology  
N-Channel Enhancement Mode

## Features

- 2nd generation SiC MOSFET technology
- High blocking voltage with low On-Resistance
- High speed switching with low capacitances
- Resistant to latch-up
- Halogen Free, RoHS Compliant

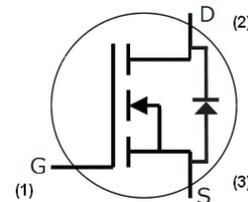
## Benefits

- Higher system efficiency
- Reduced cooling requirements
- Increased power density
- Increased system switching frequency

## Applications

- Solar inverters
- Switch Mode Power Supplies
- High voltage DC/DC converters
- Motor drive
- Pulsed power applications

## Package



Part Number	Package	Marking
C2M0045170D	TO-247-3L	C2M0045170D

## Maximum Ratings ( $T_c = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions	Note
$V_{DSmax}$	Drain - Source Voltage	1700	V	$V_{GS} = 0\text{ V}, I_D = 100\ \mu\text{A}$	
$V_{GSmax}$	Gate - Source Voltage	-10/+25	V	Absolute maximum values, AC ( $f > 1\text{ Hz}$ )	Note: 1
$V_{GSop}$	Gate - Source Voltage	-5/+20	V	Recommended operational values	Note: 2
$I_D$	Continuous Drain Current	75	A	$V_{GS} = 20\text{ V}, T_c = 25^\circ\text{C}$	Fig. 19
		48		$V_{GS} = 20\text{ V}, T_c = 100^\circ\text{C}$	
$I_{D(pulse)}$	Pulsed Drain Current	160	A	Pulse width $t_p$ limited by $T_{jmax}$	Fig. 22
$P_D$	Power Dissipation	338	W	$T_c = 25^\circ\text{C}, T_j = 150^\circ\text{C}$	Fig. 20
$T_J, T_{stg}$	Operating Junction and Storage Temperature	-40 to +150	$^\circ\text{C}$		
$T_L$	Solder Temperature	260	$^\circ\text{C}$	1.6mm (0.063") from case for 10s	
$M_d$	Mounting Torque	1	Nm lbf-in	M3 or 6-32 screw	
		8.8			

Note (1): When using MOSFET Body Diode  $V_{GSmax} = -5\text{V}/+25\text{V}$

Note (2): MOSFET can also safely operate at  $0/+20\text{V}$

**Electrical Characteristics** ( $T_C = 25^\circ\text{C}$  unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions	Note
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	1700			V	$V_{GS} = 0\text{ V}, I_D = 100\ \mu\text{A}$	
$V_{GS(th)}$	Gate Threshold Voltage	2.0	3.0	4	V	$V_{DS} = V_{GS}, I_D = 18\text{mA}$	Fig. 11
			2.5		V	$V_{DS} = V_{GS}, I_D = 18\text{mA}, T_J = 150^\circ\text{C}$	
$I_{DSS}$	Zero Gate Voltage Drain Current		2	100	$\mu\text{A}$	$V_{DS} = 1700\text{ V}, V_{GS} = 0\text{ V}$	
$I_{GSS}$	Gate-Source Leakage Current			600	nA	$V_{GS} = 20\text{ V}, V_{DS} = 0\text{ V}$	
$R_{DS(on)}$	Drain-Source On-State Resistance		40	70	m $\Omega$	$V_{GS} = 20\text{ V}, I_D = 50\text{ A}$	Fig. 4,5,6
			80			$V_{GS} = 20\text{ V}, I_D = 50\text{ A}, T_J = 150^\circ\text{C}$	
$g_{fs}$	Transconductance		24.7		S	$V_{DS} = 20\text{ V}, I_{DS} = 50\text{ A}$	Fig. 7
			23.4			$V_{DS} = 20\text{ V}, I_{DS} = 50\text{ A}, T_J = 150^\circ\text{C}$	
$C_{iss}$	Input Capacitance		3455		pF	$V_{GS} = 0\text{ V}$ $V_{DS} = 1200\text{ V}$ $f = 1\text{ MHz}$ $V_{AC} = 25\text{ mV}$	Fig. 17,18
$C_{oss}$	Output Capacitance		171				
$C_{rss}$	Reverse Transfer Capacitance		6.7				
$E_{oss}$	$C_{oss}$ Stored Energy		139				Fig 16
$C_{o(er)}$	Effective Output Capacitance (Energy Related)		188		pF	$V_{GS} = 0\text{ V}, V_{DS} = 0 \dots 1200\text{V}$	Note: 3
$C_{o(tr)}$	Effective Output Capacitance (Time Related)		255				
$E_{ON}$	Turn-On Switching Energy (SiC Diode FWD)		2.5		mJ	$V_{DS} = 1200\text{ V}, V_{GS} = -5/20\text{ V},$ $I_D = 50\text{ A}, R_{G(ext)} = 2.5\ \Omega, L = 99\ \mu\text{H},$ $T_J = 150^\circ\text{C},$ using SiC Diode as FWD	Fig. 26, 29b Note 2
$E_{OFF}$	Turn Off Switching Energy (SiC Diode FWD)		1.4				
$E_{ON}$	Turn-On Switching Energy (Body Diode FWD)		4.9		mJ	$V_{DS} = 1200\text{ V}, V_{GS} = -5/20\text{ V},$ $I_D = 50\text{ A}, R_{G(ext)} = 2.5\ \Omega, L = 99\ \mu\text{H},$ $T_J = 150^\circ\text{C},$ using MOSFET as FWD	Fig. 26, 29a Note 2
$E_{OFF}$	Turn Off Switching Energy (Body Diode FWD)		1.1				
$t_{d(on)}$	Turn-On Delay Time		68		ns	$V_{DD} = 1200\text{ V}, V_{GS} = -5/20\text{ V}$ $I_D = 50\text{ A},$ $R_{G(ext)} = 2.5\ \Omega,$ Timing relative to $V_{DS}$ Inductive load	Fig. 27, 29 Note 2
$t_r$	Rise Time		19				
$t_{d(off)}$	Turn-Off Delay Time		35				
$t_f$	Fall Time		19				
$R_{G(int)}$	Internal Gate Resistance		1.3		$\Omega$	$f = 1\text{ MHz}, V_{AC} = 25\text{ mV}$	
$Q_{gs}$	Gate to Source Charge		43		nC	$V_{DS} = 1200\text{ V}, V_{GS} = -5/20\text{ V}$ $I_D = 50\text{ A}$ Per IEC60747-8-4 pg 21	Fig. 12
$Q_{gd}$	Gate to Drain Charge		74				
$Q_g$	Total Gate Charge		200				

Note (3):  $C_{o(er)}$ , a lumped capacitance that gives same stored energy as  $C_{oss}$  while  $V_{ds}$  is rising from 0 to 1200V  
 $C_{o(tr)}$ , a lumped capacitance that gives same charging time as  $C_{oss}$  while  $V_{ds}$  is rising from 0 to 1200V

### Reverse Diode Characteristics

Symbol	Parameter	Typ.	Max.	Unit	Test Conditions	Note
$V_{SD}$	Diode Forward Voltage	3.8		V	$V_{GS} = -5\text{ V}, I_{SD} = 25\text{ A}$	Fig. 8, 9, 10 Note 1
		3.4		V	$V_{GS} = -5\text{ V}, I_{SD} = 25\text{ A}, T_J = 150\text{ }^\circ\text{C}$	
$I_S$	Continuous Diode Forward Current		76	A	$V_{GS} = -5\text{ V}, T_C = 25\text{ }^\circ\text{C}$	Note 1
$I_{S,pulse}$	Diode pulse Current		160	A	$V_{GS} = -5\text{ V}$ , pulse width $t_p$ limited by $T_{jmax}$	Note 1
$t_{rr}$	Reverse Recovery Time	53		ns	$V_{GS} = -5\text{ V}, I_{SD} = 50\text{ A}, V_R = 1200\text{ V}$ $dif/dt = 1000\text{ A}/\mu\text{s}, T_J = 150\text{ }^\circ\text{C}$	
$Q_{rr}$	Reverse Recovery Charge	461		nC		
$I_{rrm}$	Peak Reverse Recovery Current	14		A		
$t_{rr}$	Reverse Recovery Time	40		ns	$V_{GS} = -5\text{ V}, I_{SD} = 50\text{ A}, V_R = 1200\text{ V}$ $dif/dt = 3040\text{ A}/\mu\text{s}, T_J = 150\text{ }^\circ\text{C}$	
$Q_{rr}$	Reverse Recovery Charge	481		nC		
$I_{rrm}$	Peak Reverse Recovery Current	22		A		

### Thermal Characteristics

Symbol	Parameter	Typ.	Max.	Unit	Test Conditions	Note
$R_{\theta JC}$	Thermal Resistance from Junction to Case	0.25	0.37	°C/W		Fig. 21
$R_{\theta JC}$	Thermal Resistance from Junction to Ambient		40			

Typical Performance

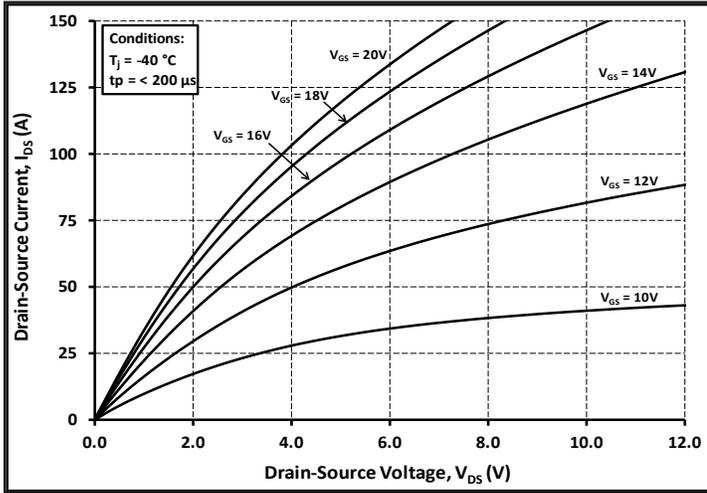


Figure 1. Output Characteristics  $T_J = -40\text{ }^\circ\text{C}$

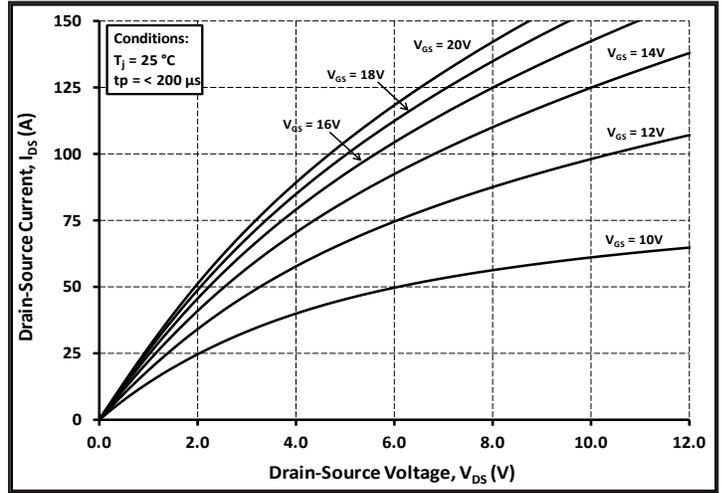


Figure 2. Output Characteristics  $T_J = 25\text{ }^\circ\text{C}$

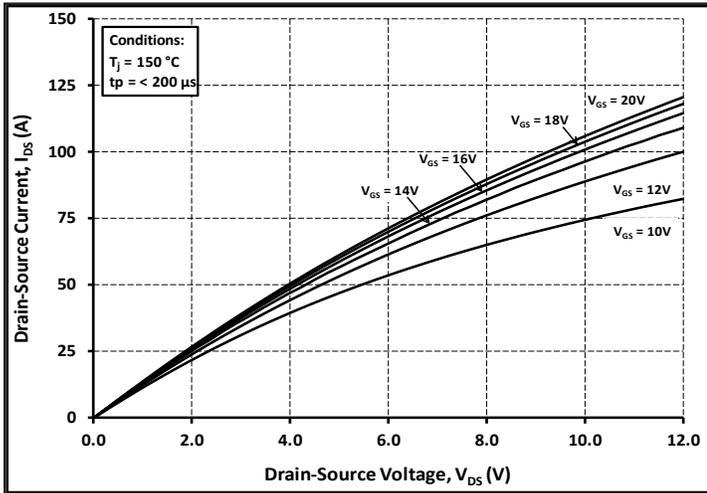


Figure 3. Output Characteristics  $T_J = 150\text{ }^\circ\text{C}$

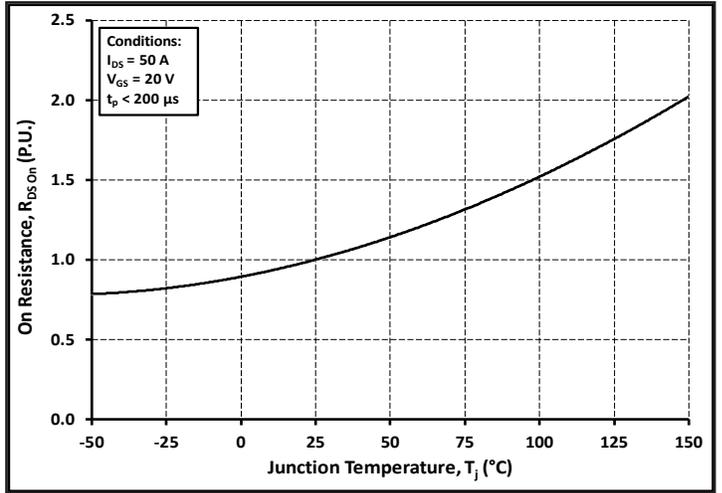


Figure 4. Normalized On-Resistance vs. Temperature

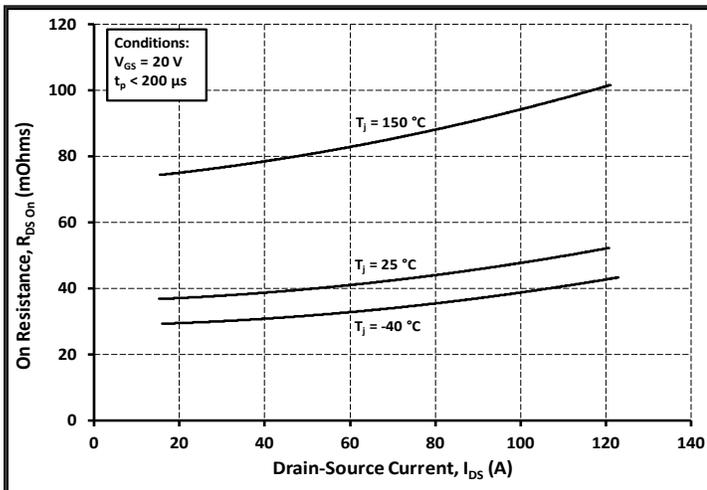


Figure 5. On-Resistance vs. Drain Current For Various Temperatures

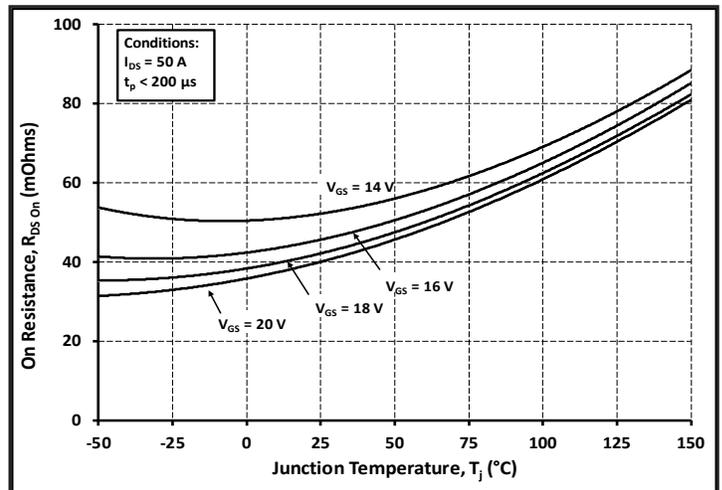


Figure 6. On-Resistance vs. Temperature For Various Gate Voltage

**Typical Performance**

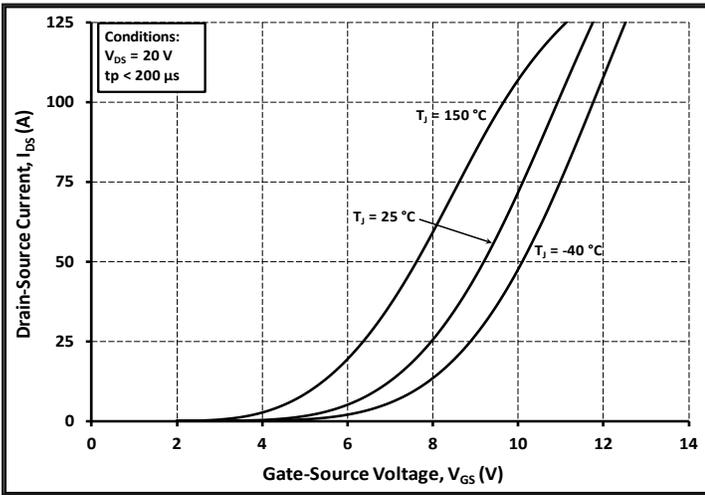


Figure 7. Transfer Characteristic For Various Junction Temperatures

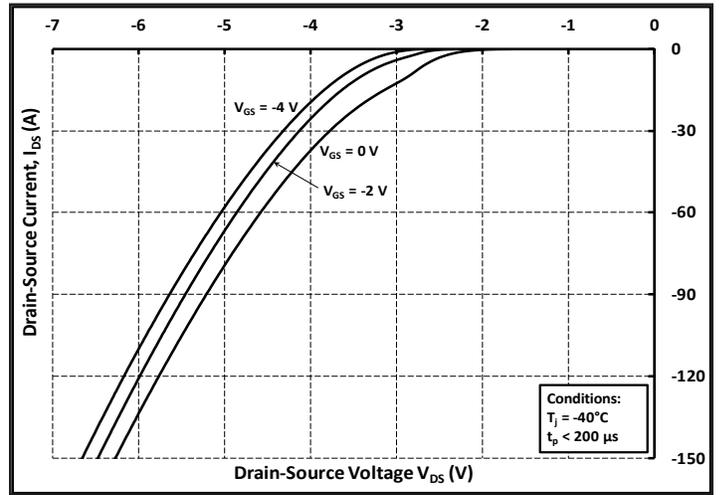


Figure 8. Body Diode Characteristic at -40 °C

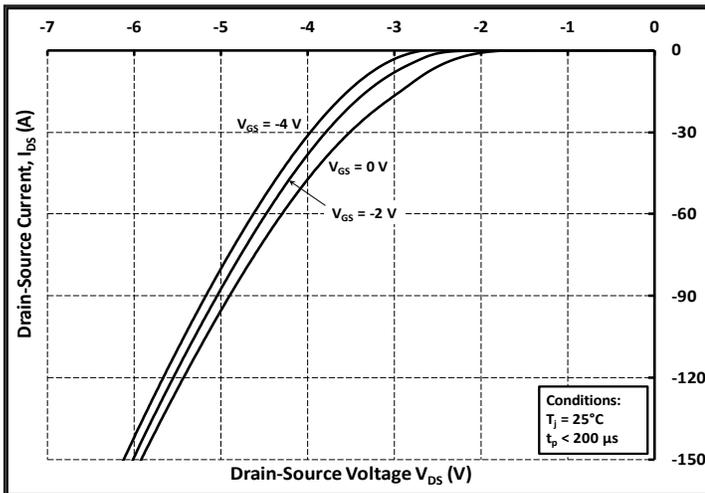


Figure 9. Body Diode Characteristic at 25 °C

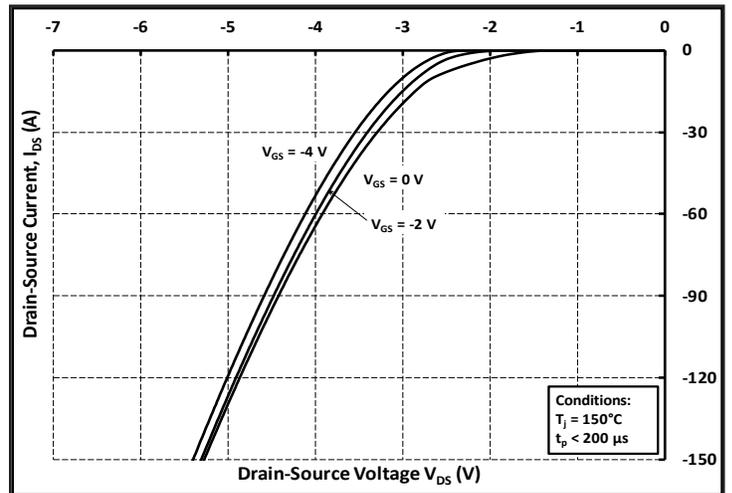


Figure 10. Body Diode Characteristic at 150 °C

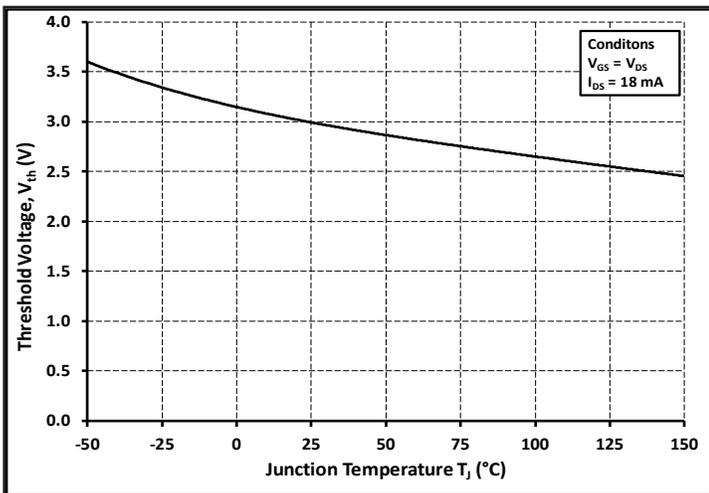


Figure 11. Threshold Voltage vs. Temperature

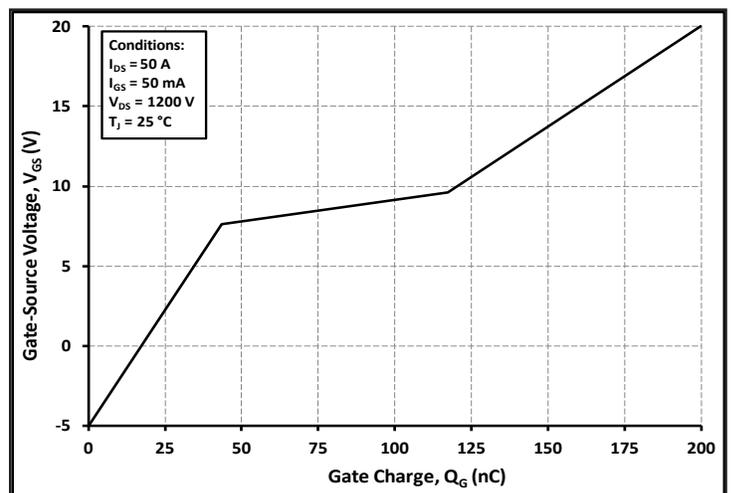


Figure 12. Gate Charge Characteristic

**Typical Performance**

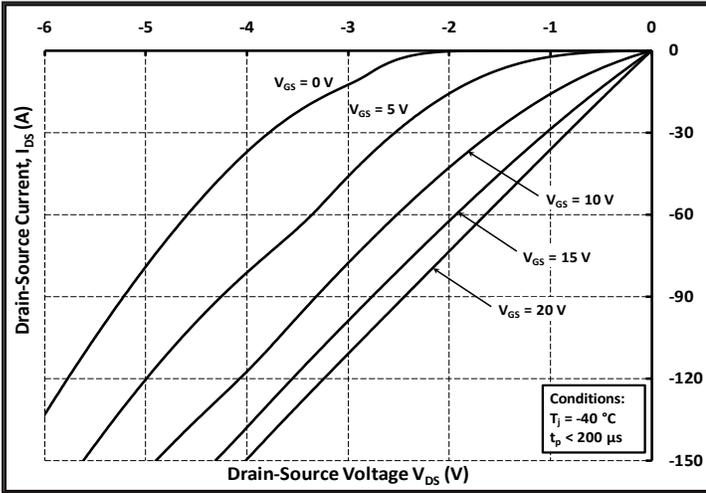


Figure 13. 3rd Quadrant Characteristic at -40 °C

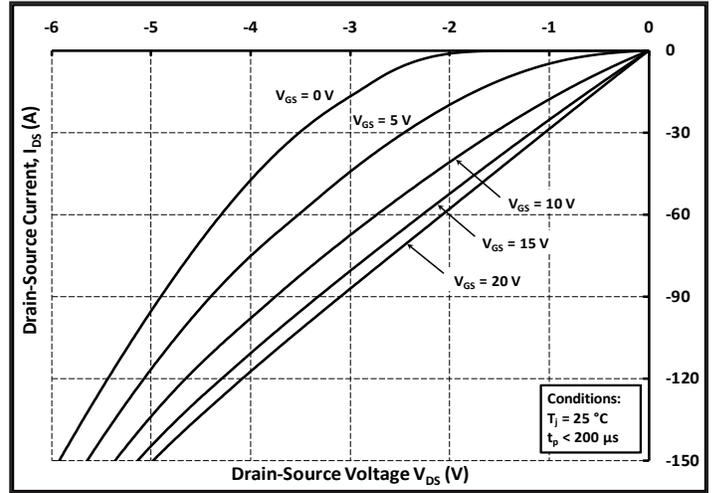


Figure 14. 3rd Quadrant Characteristic at 25 °C

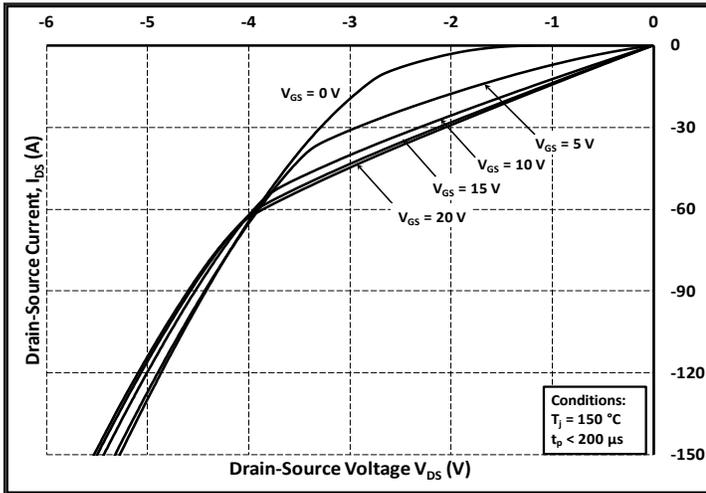


Figure 15. 3rd Quadrant Characteristic at 150 °C

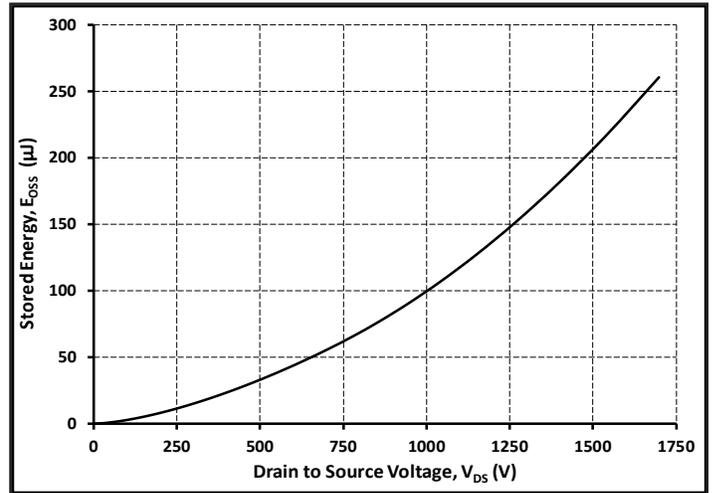


Figure 16. Output Capacitor Stored Energy

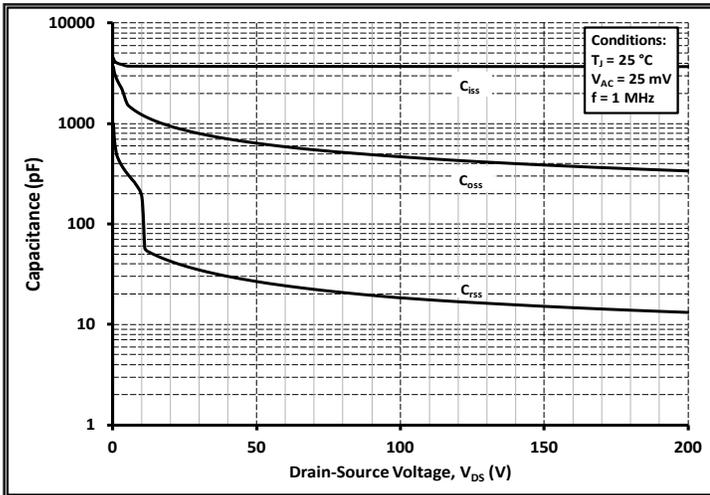


Figure 17. Capacitances vs. Drain-Source Voltage (0-200 V)

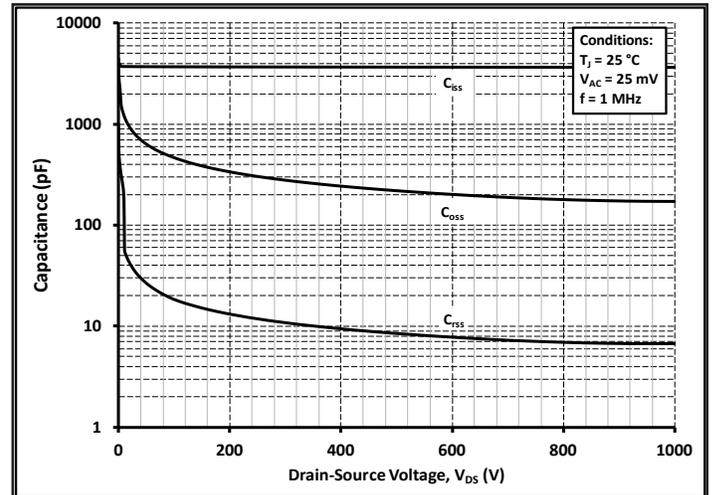


Figure 18. Capacitances vs. Drain-Source Voltage (0-1000 V)

Typical Performance

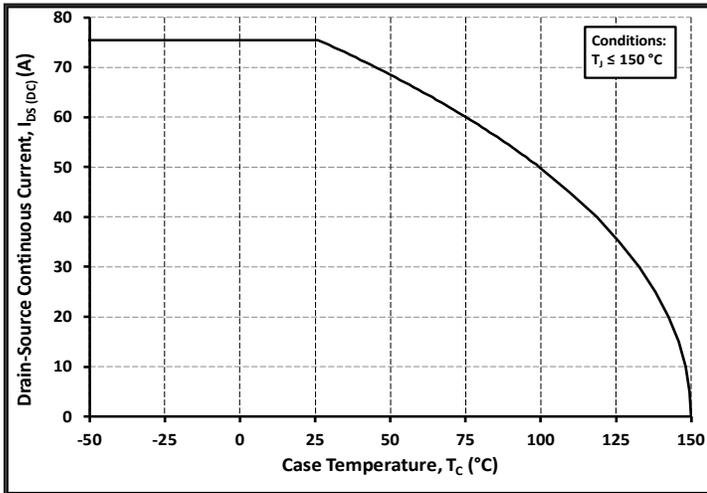


Figure 19. Continuous Drain Current Derating vs. Case Temperature

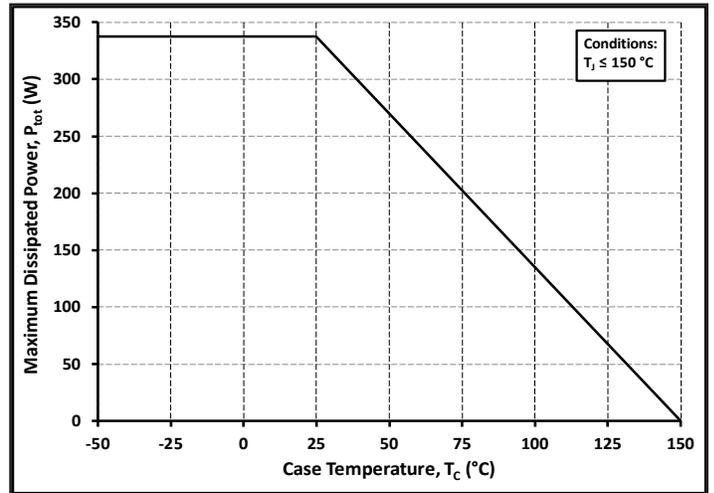


Figure 20. Maximum Power Dissipation Derating vs. Case Temperature

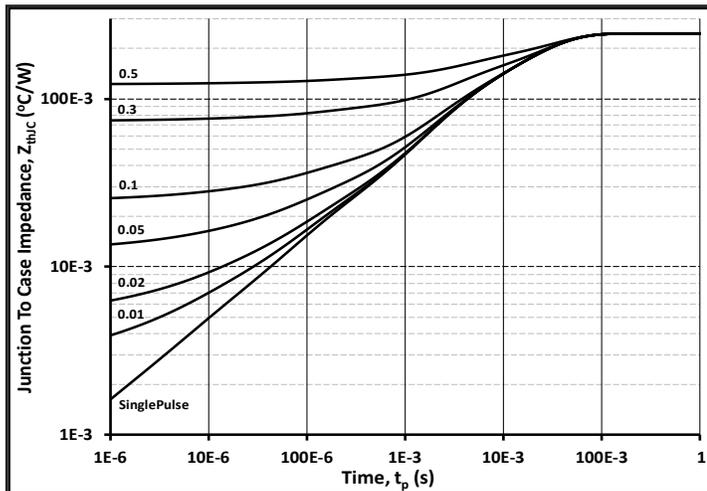


Figure 21. Transient Thermal Impedance (Junction - Case)

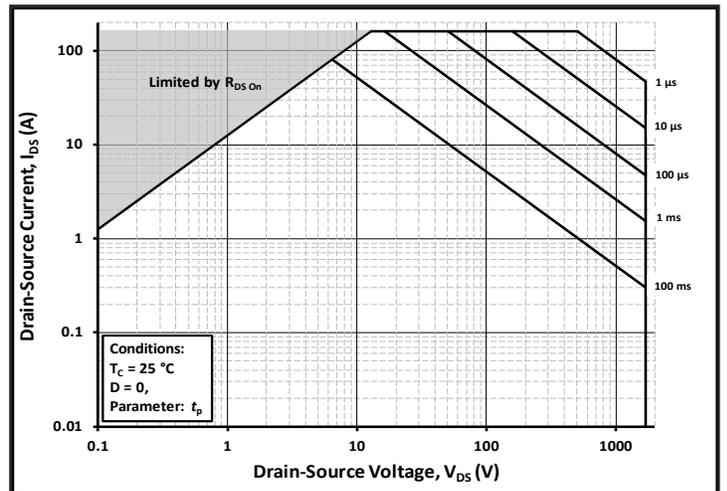


Figure 22. Safe Operating Area

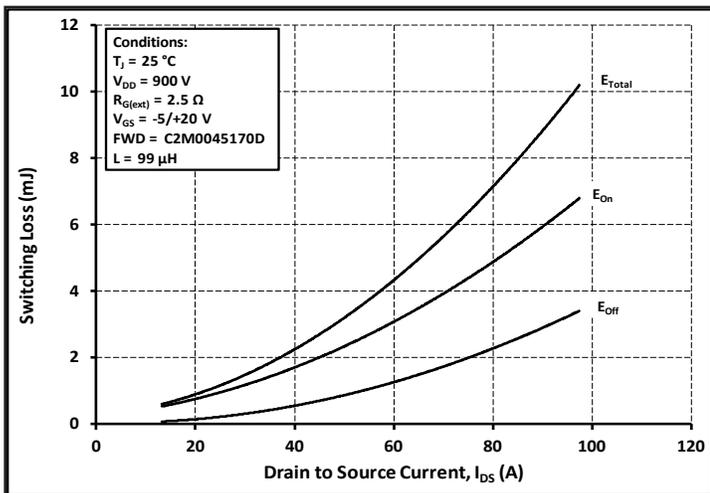


Figure 23. Clamped Inductive Switching Energy vs. Drain Current ( $V_{DD} = 900V$ )

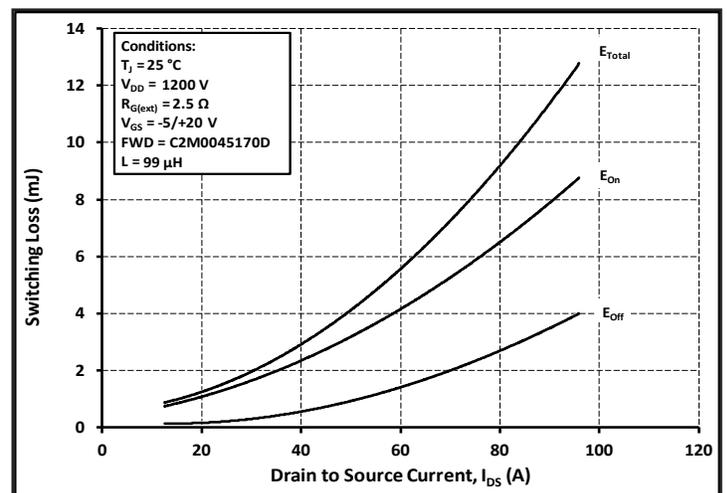


Figure 24. Clamped Inductive Switching Energy vs. Drain Current ( $V_{DD} = 1200V$ )

Typical Performance

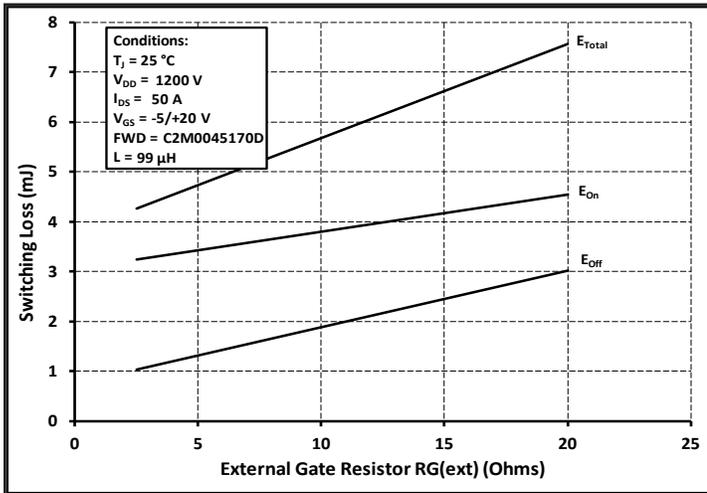


Figure 25. Clamped Inductive Switching Energy vs.  $R_{G(ext)}$

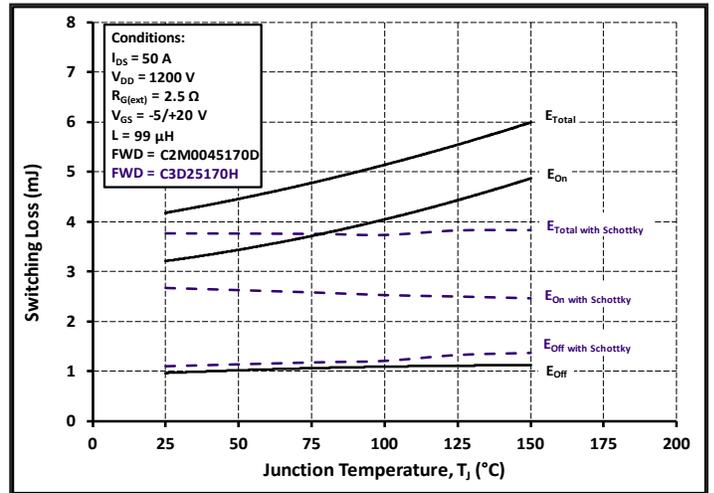


Figure 26. Clamped Inductive Switching Energy vs. Temperature

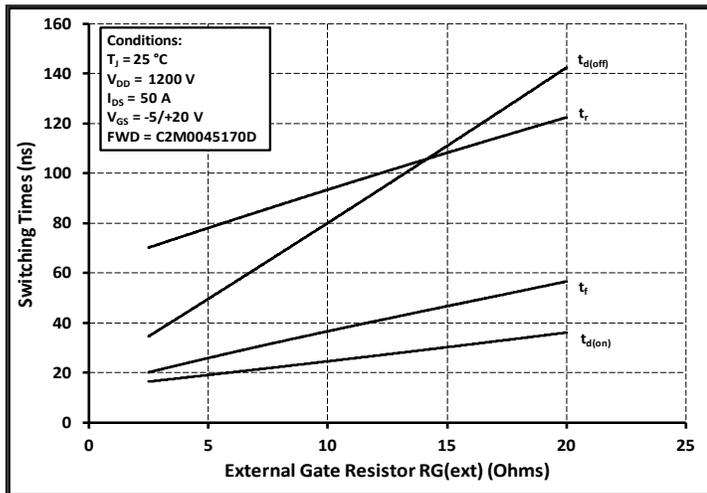


Figure 27. Switching Times vs.  $R_{G(ext)}$

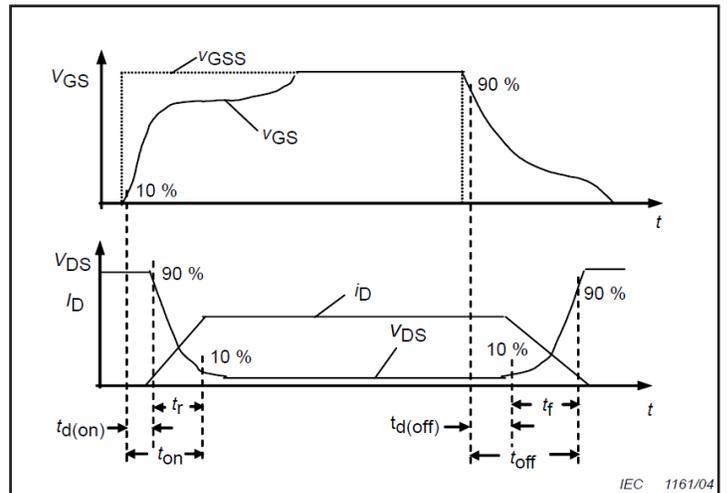


Figure 28. Switching Times Definition

**Test Circuit Schematic**

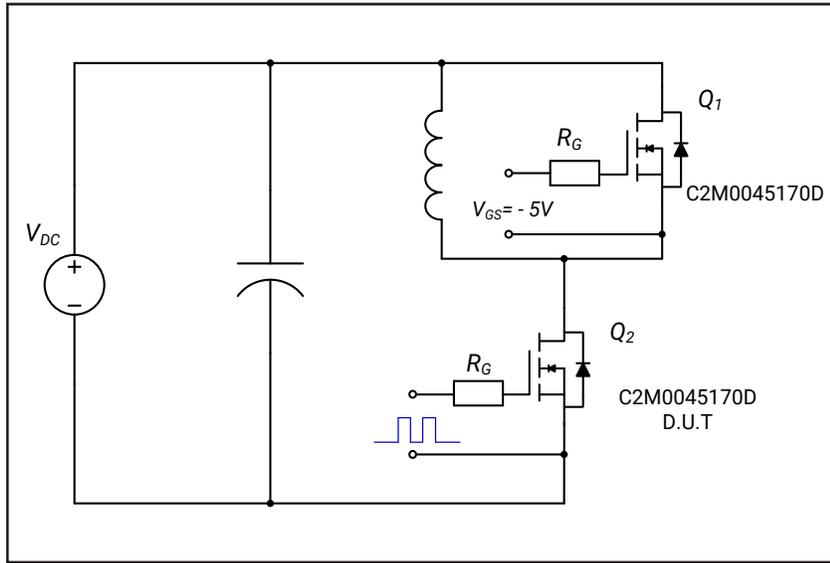


Figure 29a. Clamped Inductive Switching Test Circuit using MOSFET intrinsic body diode

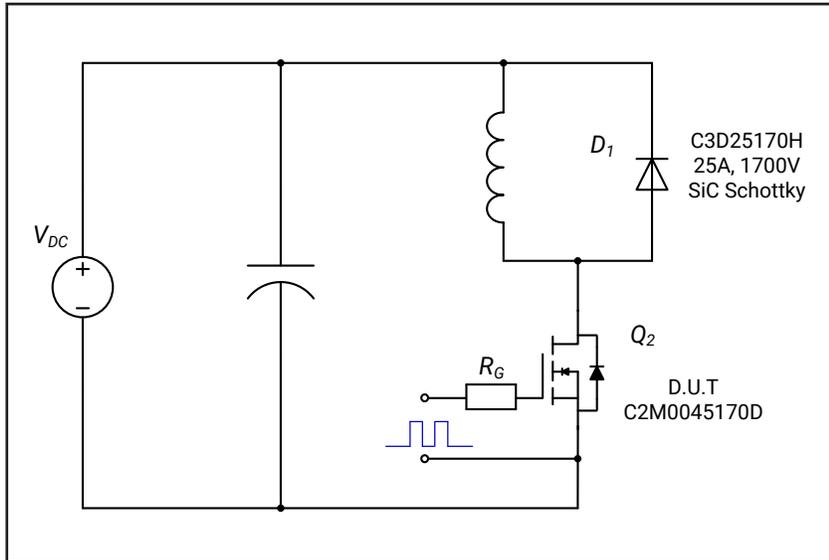
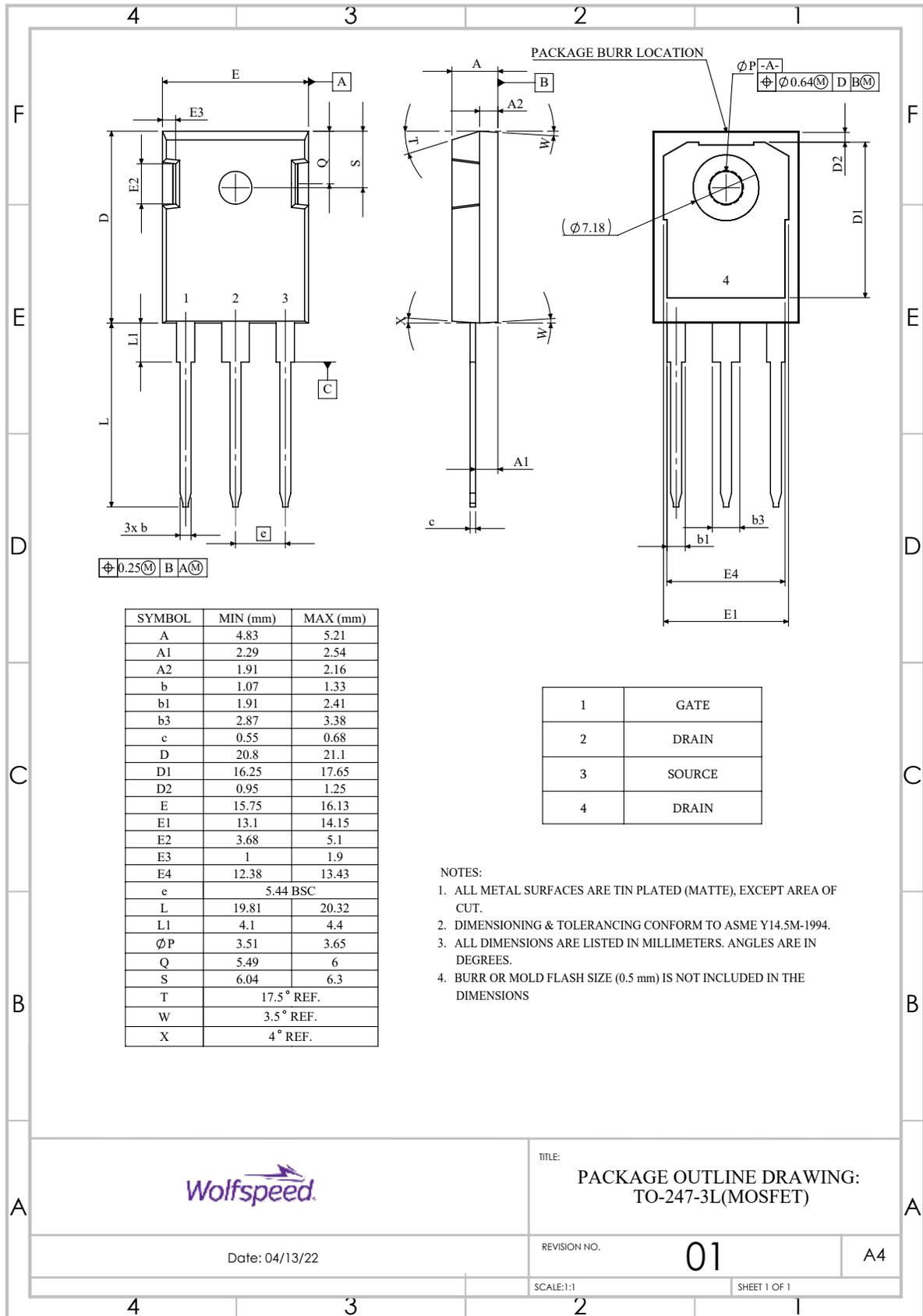


Figure 29b. Clamped Inductive Switching Test Circuit using SiC Schottky diode

**Package Dimensions**



TITLE: PACKAGE OUTLINE DRAWING: TO-247-3L(MOSFET)

Date: 04/13/22

REVISION NO.

01

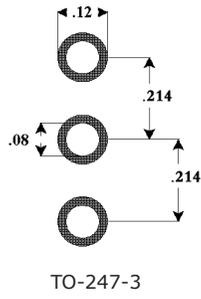
A4

SCALE:1:1

SHEET 1 OF 1

### Recommended Solder Pad Layout

---



**Revision history**

Document Version	Date of release	Description of changes
Rev -	June - 2016	Initial datasheet
Rev 1	May - 2022	Added effective output capacitance, Typical values updated to support PCN-1278.

**Note:**

This document and the information contained herein are subject to change without notice. Any such change shall be evidenced by the publication of an updated version of this document by Wolfspeed. No communication from any employee or agent of Wolfspeed or any third party shall effect an amendment or modification of this document. No responsibility is assumed by Wolfspeed for any infringement of patents or other rights of third parties which may result from use of the information contained herein. No license is granted by implication or otherwise under any patent or patent rights of Wolfspeed.

Notwithstanding any application-specific information, guidance, assistance, or support that Wolfspeed may provide, the buyer of this product is solely responsible for determining the suitability of this product for the buyer's purposes, including without limitation for use in the applications identified in the next bullet point, and for the compliance of the buyers' products, including those that incorporate this product, with all applicable legal, regulatory, and safety-related requirements.

This product has not been designed or tested for use in, and is not intended for use in, applications in which failure of the product would reasonably be expected to cause death, personal injury, or property damage, including but not limited to equipment implanted into the human body, life-support machines, cardiac defibrillators, and similar emergency medical equipment, aircraft navigation, communication, and control systems, aircraft power and propulsion systems, air traffic control systems, and equipment used in the planning, construction, maintenance, or operation of nuclear facilities.

**RoHS Compliance**

The levels of RoHS restricted materials in this product are below the maximum concentration values (also referred to as the threshold limits) permitted for such substances, or are used in an exempted application, in accordance with EU Directive 2011/65/EC (RoHS2), as implemented January 2, 2013. RoHS Declarations for this product can be obtained from your Wolfspeed representative or from the Product Documentation sections of [www.Wolfspeed.com](http://www.Wolfspeed.com).

**REACH Compliance**

REACH substances of high concern (SVHCs) information is available for this product. Since the European Chemical Agency (ECHA) has published notice of their intent to frequently revise the SVHC listing for the foreseeable future, please contact your Wolfspeed representative to ensure you get the most up-to-date REACH SVHC Declaration. REACH banned substance information (REACH Article 67) is also available upon request.

For more information please contact:  
4600 Silicon Drive Durham, NC 27703 USA  
Tel: +1.919.313.5300  
[www.wolfspeed.com/power](http://www.wolfspeed.com/power)